

ECFA DRD7 Meeting



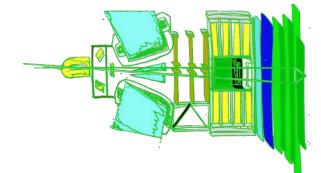


4D FOR CALO CHALLENGES: FOCUS ON LHCB ECAL UPGRADE

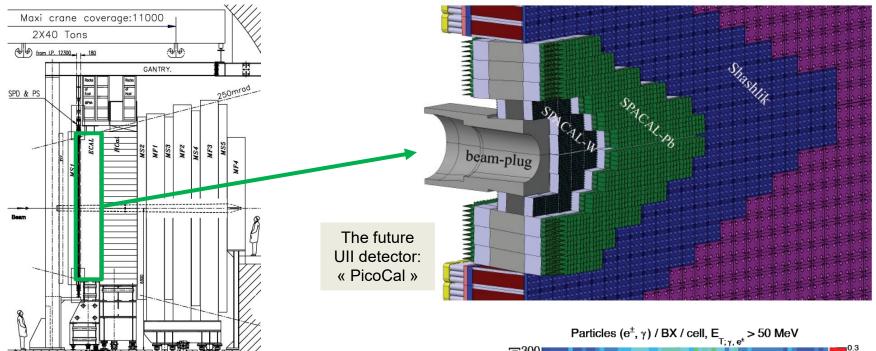
Dominique Breton, on behalf of LHCb upgrade team



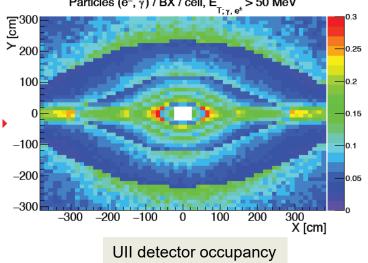
CERN, March 14th 2023



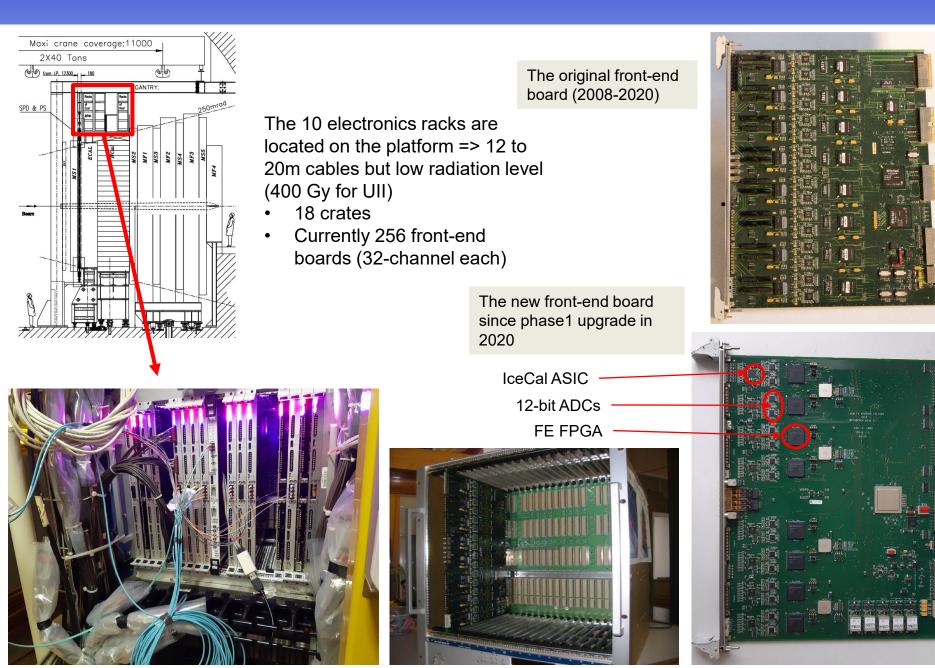
THE UII DETECTOR



- For the phase 2 upgrade, the central part of the detector will be equipped with SPACAL modules to deal with radiation (up to 1MGy).
- Shashlik will remain in the outer part (< 40kGy).
- In order to limit the occupancy, the size of the modules will be reduced thus their number increased
 - \Rightarrow from 6,000 to ~ 15,000 channels
- Introduction of longitudinal segmentation and double sided readout => ~ 30,000 channels (baseline option)



THE ELECTRONICS



REQUIREMENTS FOR NEW TIMING PATH

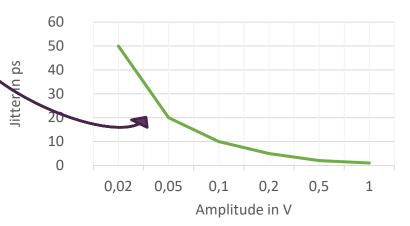
- Target time resolution of **15ps rms** to distinguish multiple interactions
- Target energy range for time measurement => $E_T = [50 MeV-5 GeV] =>$ range of 100 ...
- Deal with maximum possible channel occupancy

Theoretical electronics time resolution: $\delta_t = \frac{t_{rise\ time}}{SNR} = \frac{Noise}{Slope}$

- If you look at the current modules and electronics: rise time of 5ns with 1mV rms noise → jitter of 250ps rms !
- \Rightarrow We have to reduce **both rise time and noise**
- ⇒ To give an idea, to get a resolution of 20ps rms with a rise time of 1ns and a noise of 1mV rms, you need a 50 mV pulse
- 1ns seems to be a (below the ?) limit for the PMTs so we have to do our best concerning the noise to get the largest possible dynamic range
 - Noise is the sum of detector and electronics contributions

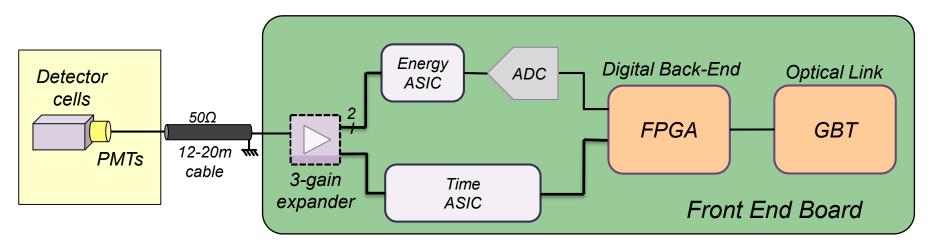
σ_a *σ*_a *σ*_j

Evolution of the jitter with the signal amplitude (rise time = 1 ns, noise = 1mV)



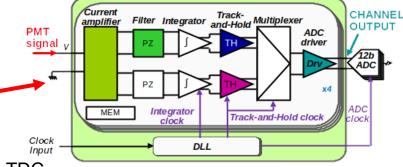
NEW ELECTRONICS CHAIN

> Chosen architecture: this choice will be explained in the following slides...



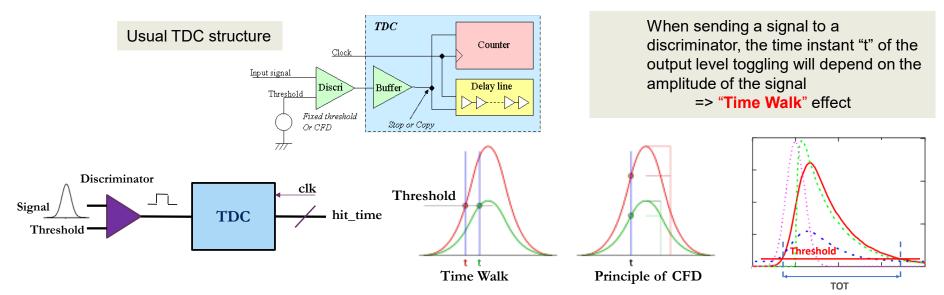
Two separated processing paths with dedicated ASICs in the same technology: CMOS 65 nm

- Energy path close to the current ICECAL scheme (mostly analog processing)
- Independent timing path based on SPIDER waveform TDC
 => can be used for other application or type of detector
- > For dynamic range compatibilities, **3 different gains** must be provided
 - 50MeV to 100GeV over 2 gains for energy measurement
 - ➢ 50MeV to 5GeV (single gain) for time measurement



DRAWBACKS OF TDC-BASED CHAINS

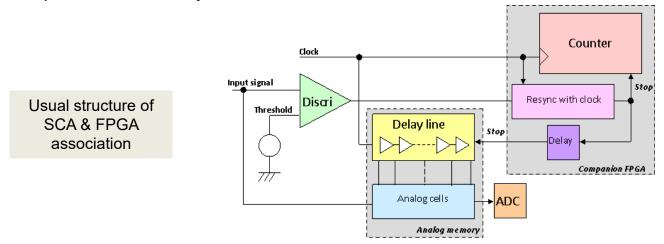
- **Time to Digital Converters (TDCs)** are the usual candidates for time stamping of fast signals. They are designed either in the form of **dedicated ASIC** or integrated inside **high-end FPGAs**.
- They are self-triggering and can withstand high counting rates
- A TDC has a strictly digital input => a discriminator has to be present to transform the analog signal into digital. It introduces additional jitter and residues of time walk => the overall timing resolution is degraded to the quadratic sum of the discrimination and TDC contributions.



To avoid the Time Walk effect, one has to use a Constant Fraction Discriminator (CFD)

- But this implies that you need to know the value of the peak to apply the threshold !
- Ok for firmware or software when the signal has been digitized but not in a TDC which does not provide information on waveform, except under the derivate form of time over threshold (TOT) thus with a rather poor precision (especially because of the asymmetry of the signal edges).

- Time measurement can also be based on **Waveform Digitizing**.
- Analog memories using Switched Capacitor Arrays (SCAs) associated with FPGAs offer a smart solution for replacing ADCs, especially in terms of power, space and money budgets.
- **The discriminator is not anymore in the critical timing path**. Time information is given by association of the Timestamp Counter (few ns step), of the DLL locked on the clock to define region of interest (100 to a few 100's picoseconds minimum step), and finally of the samples of the waveform: their interpolation will give a precision of **a few picoseconds rms**.



- This requires a precise calibration of the Time Integral Non-Linearity (like for ADCs). A very good time resolution can be reached even on small analog signals (a few tens of mV).
- The main drawback of the SCAs is their readout dead-time (a few tens to ~100 µs depending on the number of samples read), which becomes a limitation at high rates. Moreover, the channels are usually commonly triggered and readout like in an oscilloscope.

EXAMPLES OF SCA-BASED FAST DIGITIZERS





4-channel Evaluation Module

DRS4 ASIC and modules (S.Ritt, PSI)



CAEN version (V1742)

Currently used for LHCb upgrade test beams

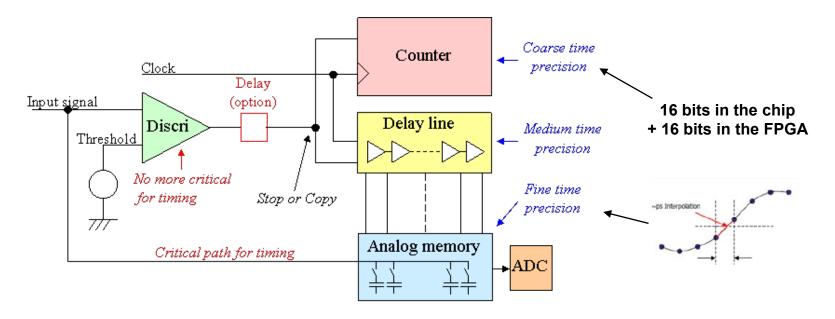
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THE « WAVEFORM TDC » STRUCTURE

 Introduced by LAL/IRFU in 2009: mix of DLL-based TDC and of analog-memory based Waveform Digitizer

- All channels are self-triggering
- The TDC gives the time of the samples and the samples give the final time precision after CFD interpolation => resolution of a few ps rms
- Digitized waveform gives access to signal shape...
- Conversely to TDC, discriminator is used only for triggering, not for timing

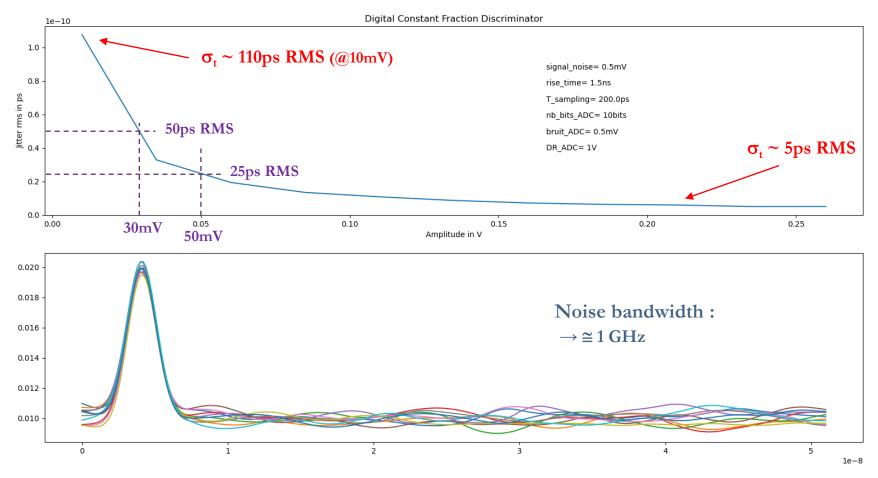


SIMULATIONS OF DIGITAL CFD (1)

Timing jitter versus signal amplitude :

rise time = 1.5ns ; σ_{noise} = 500µV_{RMS} ; σ_{SCA} = 500µV_{RMS}

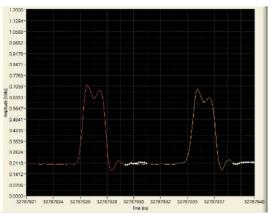
Here we use a **dynamic range of 100**, as required for ECAL: => Vin ranges from **10mV to 1V** (limited by technology)

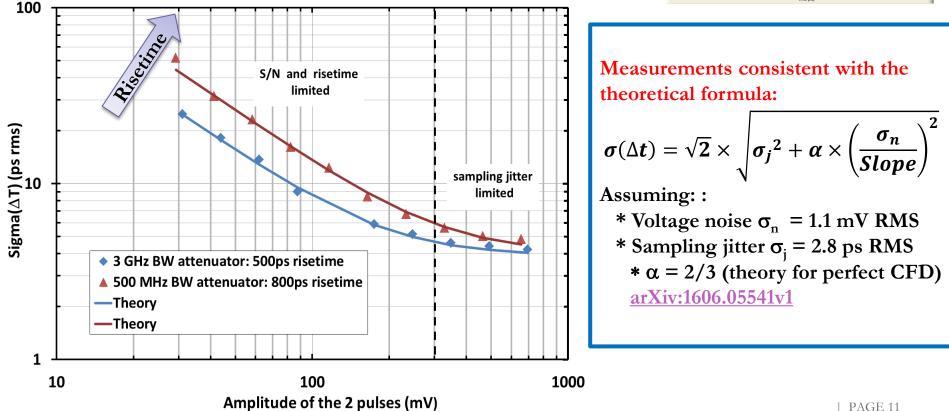


REAL MEASUREMENTS WITH DIGITAL CFD

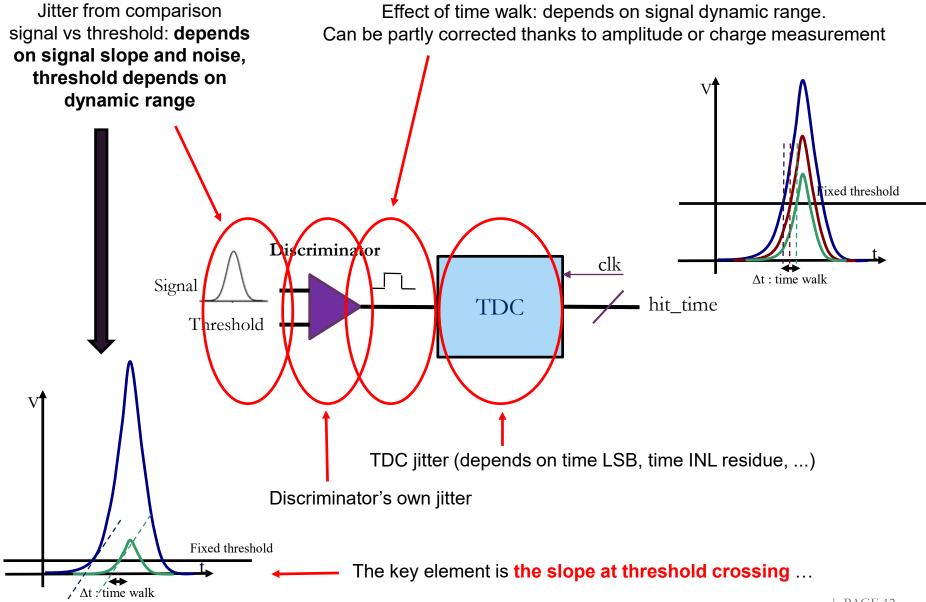
Measurements performed with a SAMPIC module (Waveform TDC, designed by IJCLAb & IRFU) : two pulses with 1nS FWHM - 15 ns delay, digital CFD algorithm







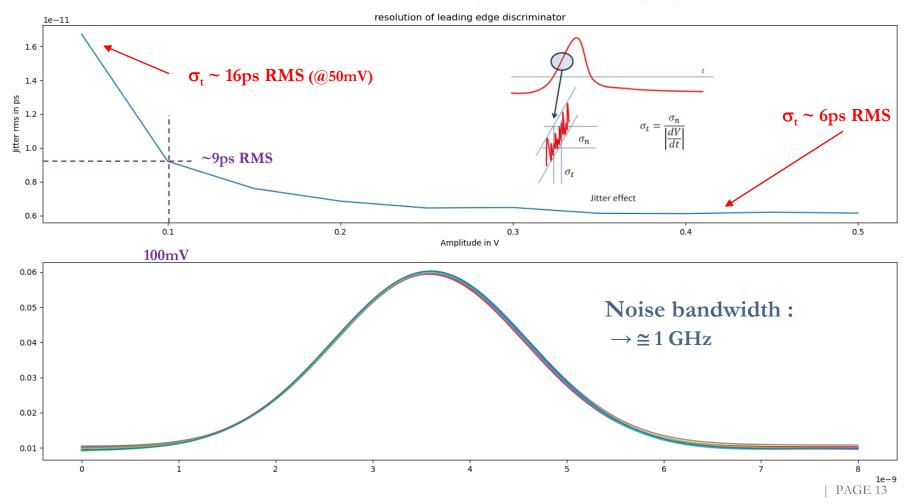
JITTER CONTRIBUTIONS IN A TDC CHAIN



SIMULATIONS OF SOLE LEADING-EDGE DISCRIMINATOR (1)

Timing jitter versus signal amplitude : rise time = 1.5ns ; σ_{noise} = 500µV RMS

- If the dynamic range was of only 20:
- Vin ranges from 50mV to 1V
- => discriminator threshold is set to 25mV (half the minimum signal)



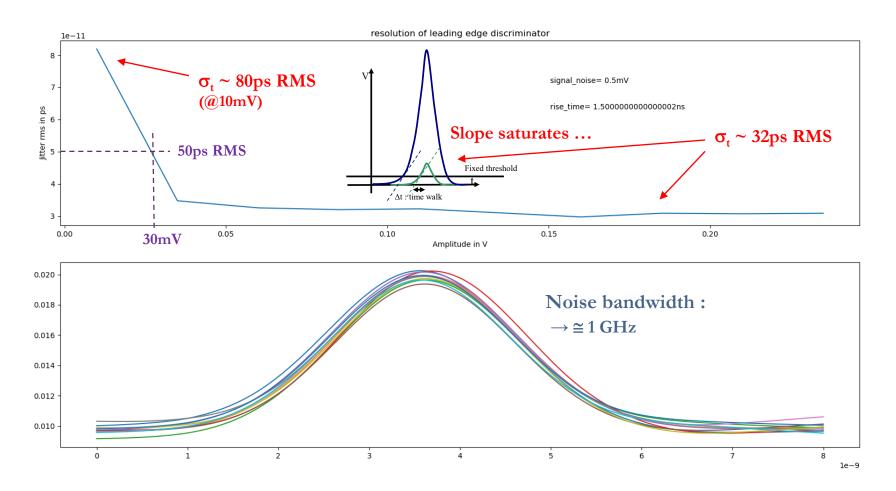
SIMULATIONS OF SOLE LEADING-EDGE DISCRIMINATOR (2)

Timing jitter versus signal amplitude : rise time = 1.5ns ; σ_{noise} = 500µVRMS

But with a dynamic range of 100:

Vin ranges from 10mV to 1V

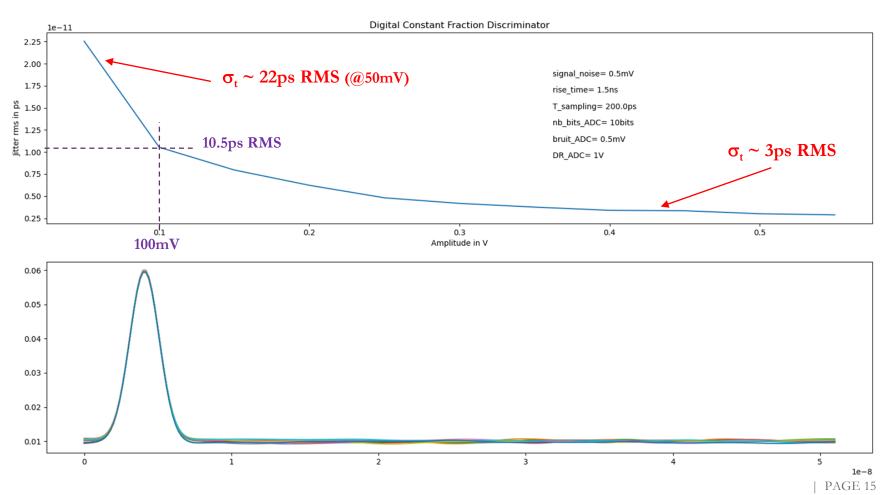
=> discriminator threshold is set to **5mV** (half the minimum signal)



Timing jitter versus signal amplitude :

rise time = 1.5ns ; σ_{noise} = 500µVRMS ; σ_{SCA} = 500µVRMS

Just to compare, here we use a reduced dynamic range of 20 => Vin ranges from 50mV to 1V

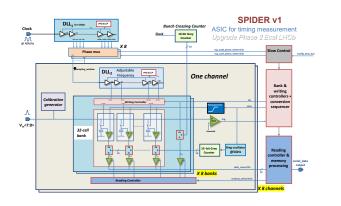


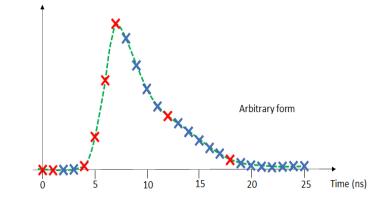
SUMMARY ABOUT DISCRIMINATOR + TDC CHAINS

- The **discriminator + TDC chain** is well adapted for small or medium dynamic ranges, not for large ones
 - Very sensitive to input noise: the contribution of the sole discriminator is already higher than the electronics target (< 20ps rms) even for large signals if input noise is > 350 μV rms.
 - Very sensitive to Time Walk correction, especially with asymmetric edges (much slower falling edge which introduces jitter in TOT)
 - In the case of LHCb, we have the separate energy measurement which could help in this field (but its correction requires a cross calibration of energy and time) => hard to predict precisely
- This kind of problems has clearly been seen on ATLAS HGTD and CMS HGCAL, even with smaller dynamic ranges than the one required for UII ECAL
 - They seem to induce non negligible limitations to the time resolution
- The **other contributions** still and always have to be added (in quadrature):
 - The **discriminator noise** => low
 - The TDC's own time resolution => depends on the chosen solution (FPGA or ASIC), and of the complexity of its calibration

INTRODUCTION TO SPIDER

- Conversely, analog memories permit covering all types of ranges with a resolution much less sensitive to input noise and to other signal specificities:
 - Their own noise adds up but is visible only for small signals
 - Their own jitter (low if well designed and calibrated) becomes dominant only for large signals
 - Calibration is simple and all calibrations signals are internally generated
 - Time extraction algorithm could be adapted to **signal shape evolution** due to aging and irradiation
 - Obviously challenging but "safe" and robust solution, compatible with dedicated timing layer option.
- The idea for **SPIDER** is to select **8 samples** on the signal which will be used for time extraction via CFD
 - \Rightarrow this will limit the analog memory readout time (40ns/evt @ 200MHz/sample)
 - ⇒ time extraction performed in the companion FPGA will be studied (requires memory for calibration data storage)



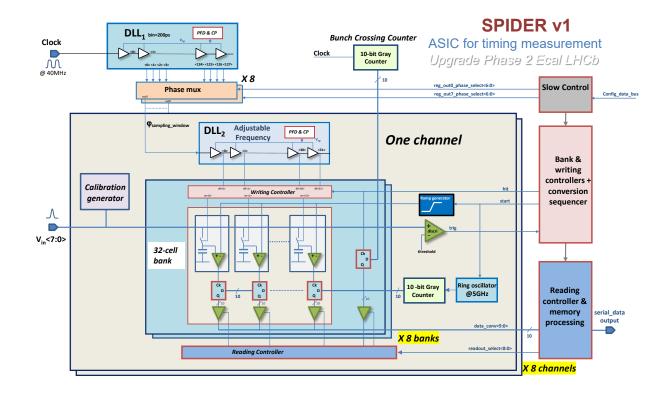


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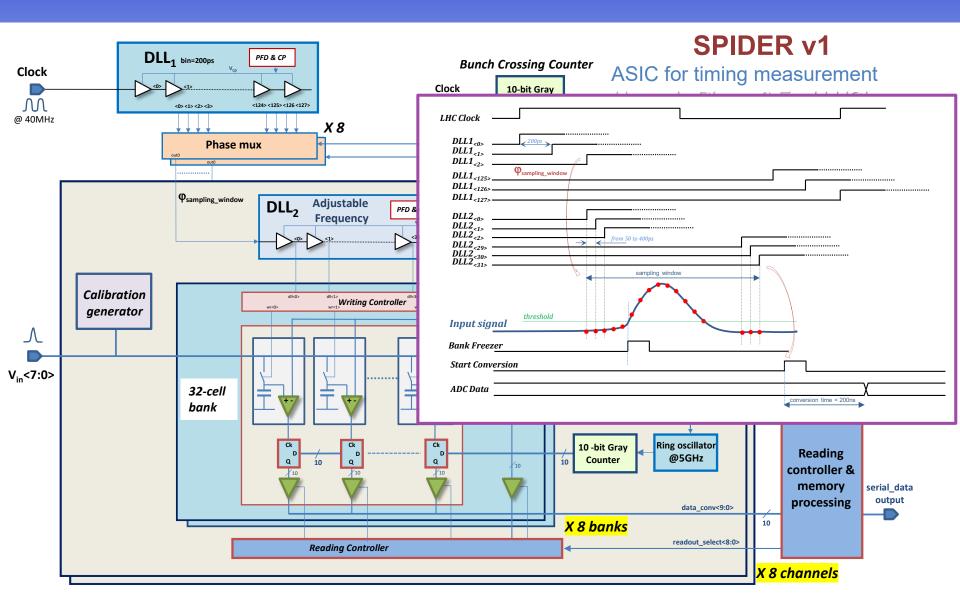
ARCHITECTURE OF SPIDER

- Each channel is **self-triggering** (based on individual discriminators)
- There are 8 banks per channel and they can trigger on consecutive BCs: analog derandomizer
 - The sampling window covers a subset of the clock period based on the time of flight of particles
- ADC is massively parallel so it can convert all the banks which have already triggered
 - => this permits increasing the mean occupancy (up to ~ 50% at the ADC level)

=> the bottleneck is pushed towards the output dataflow capacity (up to ~2Gbit/s/ch)



ROUGH SEQUENCING OF ACQUISITION



SPIDER CHARACTERISTICS

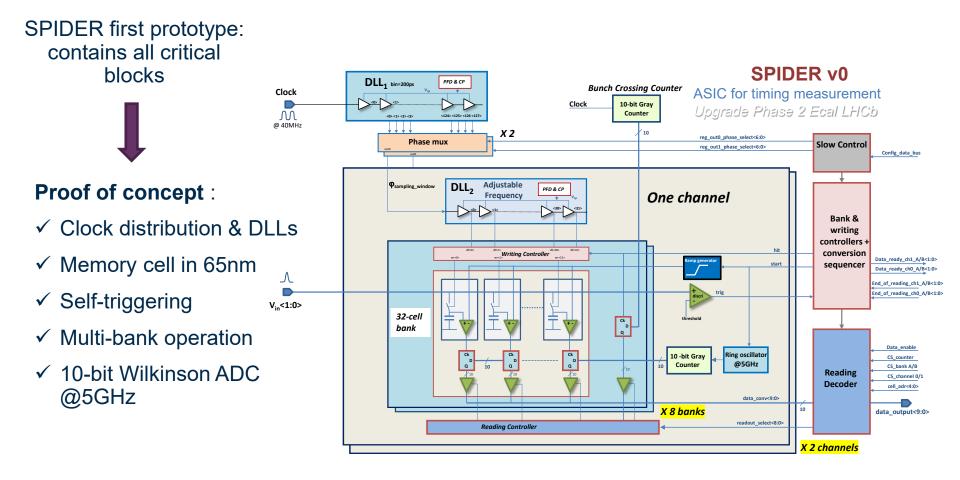
- Technology: TSMC CMOS 65nm (the most lasting technology, 10 years (?)), but only 1.2V of power supply (2.5V transistors are also available)
 - \Rightarrow hard for analog design => smart use of 2.5V transistors
 - \Rightarrow nice for digital blocks
- Input signal: rise time ~ 1ns / 1.5ns, dynamic range V_{in}=[10mV-1V]

To achieve the time resolution of 15ps rms over the largest possible energy range, we need :

- a memory cell (switches & capacitor) with ~1V of dynamic range and a noise voltage around or below 0.5mV rms
- a resolution of 10 bits for the conversion: **10-bit Wilkinson ADC running at 5GHz** to reduce the conversion time (200ns max for full 10-bit range, i-e 8 clock periods max)
- A 128-delay-cell DLL1 running @40MHz → bin ≈ 200ps to define the beginning and the width of the sampling window
- ➤ a 32-delay-cell DLL2 running from 80MHz to 640 MHz → bin ≈ 50ps to 400ps to fix the sampling frequency between 2.5GS/s and 20GS/s

FIRST PROTOTYPE ARCHITECTURE

Architecture: «two eight-bank channels»



DEVELOPMENT STATUS

- Collaboration of 4 IN2P3 labs (Orsay, Clermont-Ferrand, Caen, Lyon) led by IJCLab and LPC Clermont.
- Very challenging design! Has started six months ago.
- Repartition in work packages for:
 - 1) Delay Locked Loop (DLL1 & DLL2)
 - 2) Analog part (memory cell, trigger comparator, ADC comparator, ramp generator) + Sampling & ADC management (bank & write controller + conversion sequencer)
 - 3) Counting digital part for "10-bit Wilkinson ADC & coarse time" (Gray counters, ring oscillator)
 - 4) Slow control & Readout management part (read decoder)
 - 5) Phase Locked Loop (not critical for first prototype)



The first prototype submission is expected at the end of 2023

The idea is to start with 3,500 channels of new electronics in the inner detector for run 4. Including the new front-end boards housing SPIDER...

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CERN	Run 2 LS2			Run 3			LS3			Run 4				LS4		Run 5 - 6		
	LHC				13 TeV						14 TeV			HL	LHC			
rucp	4×10 ³² cm ⁻² s ⁻¹ 9 fb ⁻¹ Upgrade I				2×10 ³³ cm ⁻² s ⁻¹ 23 fb ⁻¹			LS3 Enhancements			2×10 ³³ cm ⁻² s ⁻¹ 50 fb ⁻¹			Upgrade II		1.5×10 ³⁴ cm ⁻² s ⁻¹ 300 fb ⁻¹		

SUMMARY

- For 4D calorimetry, we need to develop electronics with large dynamic range and very good time resolution
 - As shown, the association of the two requirements is a challenge which seems to be in the spirit of DRD7 ...
- Based on our long experience in the design of analog memories, we feel like the Waveform TDC can be an adequate solution to face this challenge
 - > Waveform indeed contains all information
 - > A low threshold has **no impact on time resolution**
 - > Extracting only the most useful samples for the time extraction limits the readout time
 - > There is a lot of bandwidth margin for faster signals which may directly reduce the jitter
 - > This solution can work for many other types of detectors ...
- > Our main targets:
 - Short term:
 - Reduce the electronics noise and increase the dynamic range
 - Reduce the conversion time while keeping the massive parallelism of the ADC
 - Get the best possible time INL and jitter for the analog memory
 - Optimize the output dataflow
 - > Longer term:
 - > Perform on-chip data compression still allowing external feature extraction
 - Get closer to 100% occupancy
 - > Measure **both energy and time** ...